

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): Farnsworth III, *et al.*

Group Art Unit: 2138

Application No.: 10/651,874

Examiner: Tabone Jr, John J.

Filing Date: 08/29/2003

Docket No.: **BUR920030103US1**

Title: **PARTIAL GOOD INTEGRATED CIRCUIT AND METHOD OF TESTING SAME**

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**OFFICE ACTION RESPONSE**

Sir:

This communication is in response to the Office Action mailed March 28, 2007.